

**Notice of References Cited**

Application/Control No.

08/960,431

Applicant(s)/Patent Under  
Reexamination  
SUGIYAMA ET AL.

Examiner

Jacob K. Ackun Jr.

Art Unit

3723

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**U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name               | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-3,568,377                                     | 03-1971         | Blohm et al.       | 451/444        |
| * | B | US-3,594,963                                     | 07-1971         | Beasley, George A. | 51/293         |
| * | C | US-3,710,517                                     | 01-1973         | Valerio et al.     | 451/42         |
| * | D | US-3,785,094                                     | 01-1974         | Holzhauer, Rudolf  | 451/532        |
| * | E | US-5,154,021                                     | 10-1992         | Bombardier et al.  | 451/444        |
| * | F | US-5,172,681                                     | 12-1992         | Ruark et al.       | 125/38         |
| * | G | US-5,235,959                                     | 08-1993         | Frank et al.       | 125/11.01      |
|   | H | US-  |                 |                    |                |
|   | I | US-  |                 |                    |                |
|   | J | US-  |                 |                    |                |
|   | K | US-  |                 |                    |                |
|   | L | US-  |                 |                    |                |
|   | M | US-  |                 |                    |                |

**FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
|   | O |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
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|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

**NON-PATENT DOCUMENTS**

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)  |
|---|---|--|
| * | U | Semiconductor International, Mar. 1992, pp.44-48, Peter H. singer, Senior Editor.  |
| * | V | Spin-On Glass for Dielectric Planarization by Satish K. Gupta, distributed through the courtesy of Allied-signal Inc., Milpitas, CA. |
| * | W | Solid State Technology May 1992, Sematech Inc., Austin, Texas. Planarizing Interlevel Dielectrics by Chemical-Mechanical Polishing.  |
| * | X | Electronics Materials, Mar. 1994, pp91-96.   |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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|   | A | US-  |                 |      |                |
|   | B | US-  |                 |      |                |
|   | C | US-  |                 |      |                |
|   | D | US-  |                 |      |                |
|   | E | US-  |                 |      |                |
|   | F | US-  |                 |      |                |
|   | G | US-  |                 |      |                |
|   | H | US-  |                 |      |                |
|   | I | US-  |                 |      |                |
|   | J | US-  |                 |      |                |
|   | K | US-  |                 |      |                |
|   | L | US-  |                 |      |                |
|   | M | US-  |                 |      |                |

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|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
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|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

**NON-PATENT DOCUMENTS**

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)       |
|---|---|---|
| * | U | Speedfam CMP-V Planarization System, The Competitive Edge. 0.35, Micron Line Width Design Rule. |
|   | V |   |
|   | W |   |
|   | X |   |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.